Electronic Supplementary Material (ESI) for Journal of Materials Chemistry C. This journal is © The Royal Society of Chemistry 2016

Supporting information

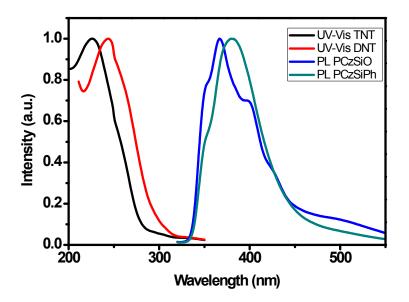


Figure S1. Uv-Vis spectra of TNT and TNT, PL spectra of PCzSiO and PCzSiPh.

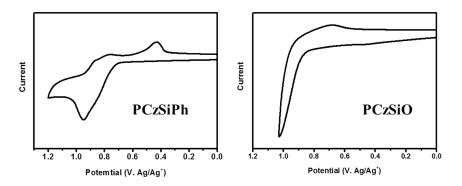


Figure S2. CV curves of PCzSiO and PCzSiPh.

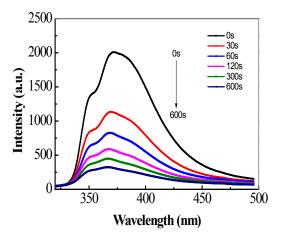


Figure S3. Time-dependent fluorescence intensity of PCzSiPh film in TNT. The film thickness is 12 nm.

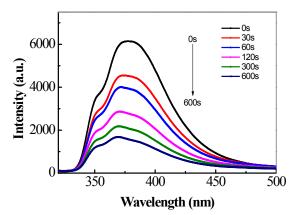


Figure S4. Time-dependent fluorescence intensity of PCzSiPh film in TNT. The film thickness is 52 nm.

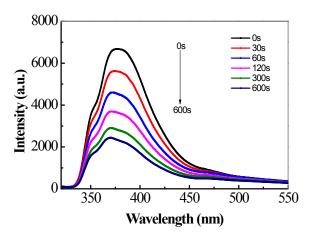


Figure S5. Time-dependent fluorescence intensity of PCzSiPh film in TNT. The film thickness is 95 nm.

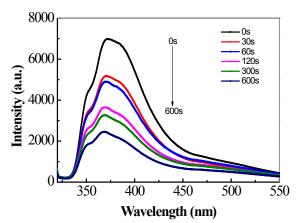


Figure S6. Time-dependent fluorescence intensity of PCzSiPh film in TNT. The film thickness is 122 nm.

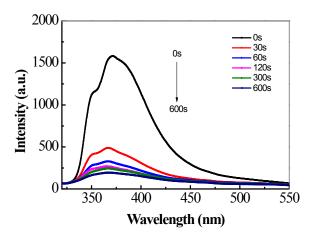


Figure S7. Time-dependent fluorescence intensity of PCzSiPh film in DNT. The film thickness is 12 nm.

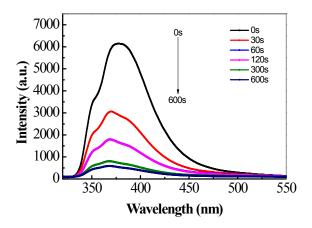


Figure S8. Time-dependent fluorescence intensity of PCzSiPh film in DNT. The film thickness is 52 nm.

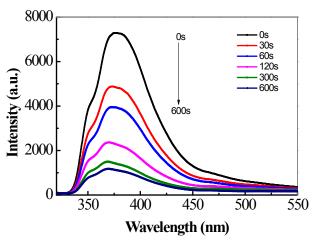


Figure S9. Time-dependent fluorescence intensity of PCzSiPh film in DNT. The film thickness is 95 nm.

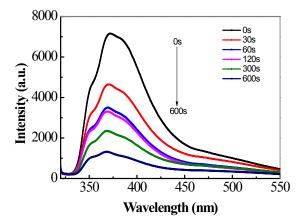


Figure S10. Time-dependent fluorescence intensity of PCzSiPh film in DNT. The film thickness is 122 nm.